

FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20244

Generic Copy

Issue Date: 24-Sep-2013

<u>TITLE</u>: Final Notification of Qualification of SP Semiconductor Korea for Assembly and Test of Bipolar Power ThermalTrak™Transistors packaged in TO-264 5L.

PROPOSED FIRST SHIP DATE: 24-Dec-2013

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Assembly & Test

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Farrah Omar <farrah.omar@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Laura Rivers rivers@onsemi.com

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

ON Semiconductor announces the qualification of SP Semiconductor Korea for Assembly and Testing of Bipolar Power ThermalTrak™ Transistors packaged in TO-264 5L, previously built at PSI Manila.

SP Semiconductor facility is ISO/TS 16949:2002 certified.

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RELIABILITY DATA SUMMARY:

Reliability Test Results:

Device NJL3281DG

Test:	Conditions:	Interval:	Results
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/160
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs	0/160
H3TRB+PC	Ta=85C RH=85% bias=80% rated V or100V Max	1008 hrs	0/160
TC+PC RSH	Ta= -65 C to 150 C Ta=260C, 10 sec dwell	1000 cyc	0/160 0/20

Device NJL1302DG

Test:	Conditions:	Interval:	Results
HTRB H3TRB+PC	Ta=150C,80% Rated Voltage Ta=85C RH=85%	1008 hrs 1008 hrs	0/240 0/159
	bias=80% rated V or100V Max		

ELECTRICAL CHARACTERISTIC SUMMARY:

There are no changes in electrical characteristics; product performance meets data sheet specifications. Characterization data is available upon request.

CHANGED PART IDENTIFICATION:

Product from SP Semiconductor will be identified by SP site code marking.

List of affected General Parts:

NJL1302DG NJL3281DG NJL0281DG NJL0302DG

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